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Session Chair: Larry V. Kirkland (WesTest Engineering, USA)

Design and Manufacturing of Launch Support Test Set For ARIRANG-3

Young-Yun Kim (Korea Aerospace Research Institute, Korea)

Dong-Chul Chae (Korea Aerospace Research Institute, Korea)

Jong-Yeoun Choi (Korea Aerospace Research Institute, Korea)

Jae-Wook Kwon (Korea Aerospace Research Institute, Korea)

Developing New Automatic Test Equipments (ATE) using Systematic Design Approaches

H. Alper Toku (ASELSAN Inc., Turkey)

Incorporating Optical Test Capabilities into a Depot Test Platform

Lowell Parsons (Marvin Test Solutions, USA)

Michael Dewey (Marvin Test Solutions, USA)

A Modular, Extendible and Reusable Test Configuration for System-Level Manufacturing Tests

Muharrem Tümçakır (ASELSAN Inc., Turkey)

Çınar Yeşil (ASELSAN Inc., Turkey)

Mert Burkay Çöteli (ASELSAN Inc., Turkey)

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Zhao Chen-xu (National University of Defense Technology, P.R. China)

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PengFei Dai (Tsinghua University, P.R. China)

Shiyuan Yang (Tsinghua University, P.R. China)

Jinxia Jiao (Tsinghua University, P.R. China)

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